

HAC RF TEST REPORT

No. I15Z40879-SEM04

For

TCL Communication Ltd.

CDMA+LTE mobile phone for Sprint

Model Name: 5017B

With

Hardware Version: VE

Software Version: 5017BA0B

FCC ID: 2ACCJB011

Results Summary: M Category = M4

Issued Date: 2015-05-25



Note:

The test results in this test report relate only to the devices specified in this report. This report shall not be reproduced except in full without the written approval of CTTL.

Test Laboratory:

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REPORT HISTORY

Report Number	Revision	Issue Date	Description
I15Z40879-SEM04	Rev.0	2015-05-25	Initial creation of test report



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1 Test Laboratory

1.1 Testing Location

Company Name:	CTTL(Shouxiang)	
Address:	No. 51 Shouxiang Science Building, Xueyuan Road, Haidian District,	
	Beijing, P. R. China100191	

1.2 Testing Environment

Ambient noise is checked and found very low and in compliance with requirement of standards. Reflection of surrounding objects is minimized and in compliance with requirement of standards

1.3 Project Data

Project Leader:	Qi Dianyuan		
Test Engineer:	Lin Hao		
Testing Start Date:	May 15, 2015		
Testing End Date:	May 15, 2015		

1.4 Signature

Lin Hao

(Prepared this test report)

Qi Dianyuan

(Reviewed this test report)

Xiao Li

Deputy Director of the laboratory

(Approved this test report)



2 Client Information

2.1 Applicant Information

Company Name:	TCL Communication Ltd.			
Address /Post:	5F, C building, No. 232, Liang Jing Road, ZhangJiang High-Tech Park,			
Address /Post.	Pudong Area, Shanghai, P.R. China. 201203			
City:	Shanghai			
Postal Code:	201203			
Country:	P.R.China			
Contact:	Zhizhou Gong			
Email:	zhizhou.gong@tcl.com			
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2.2 Manufacturer Information

Company Name:	TCL Communication Ltd.		
Address /Post:	5F, C building, No. 232, Liang Jing Road, ZhangJiang High-Tech Park,		
Address /Post:	Pudong Area, Shanghai, P.R. China. 201203		
City:	Shanghai		
Postal Code:	201203		
Country:	P.R.China		
Contact:	Zhizhou Gong		
Email:	zhizhou.gong@tcl.com		
Telephone:	+86 21 51798260		
Fax:	+86 21 61460602		



3 Equipment Under Test (EUT) and Ancillary Equipment (AE)

3.1 About EUT

Description:	CDMA+LTE mobile phone for Sprint			
Model name:	5017B			
Operating mode(s):	ng mode(s): CDMA BC0/1/10, LTE Band 25/26/41, BT, Wi-Fi			

3.2 Internal Identification of EUT used during the test

EUT ID*	IMEI	HW Version	SW Version
EUT1	089771315800065896/35820406010168	VE	5017BA0B
EUT2	089771315800065940/35820406010194	VE	5017BA0B

^{*}EUT ID: is used to identify the test sample in the lab internally.

Note: It is performed to test HAC with the EUT1 and conducted power with the EUT2.

3.3 Internal Identification of AE used during the test

AE ID*	Description	Model	SN	Manufacturer
AE1	Battery	TLi020F2	/	SCUD

^{*}AE ID: is used to identify the test sample in the lab internally.

3.4 Air Interfaces / Bands Indicating Operating Modes

Air-interface	Band(MHz) Type C63.19/tested Simultane		Simultaneous Transmissions	ОТТ	Power	
						Reduction
	BC0					
CDMA	BC1	VO	Yes	BT, WLAN	NA	NA
	BC10					
LTE	Band 25/26/41	DT	NA	BT, WLAN	NA	NA
ВТ	2450	DT	NA	CDMA, LTE	NA	NA
WLAN	2450	DT	NA	CDMA, LTE	NA	NA

VO: Voice CMRS/PSTN Service Only

V/D: Voice CMRS/PSTN and Data Service

DT: Digital Transport

^{*} HAC Rating was not based on concurrent voice and data modes, Non current mode was found to represent worst case rating for both M and T rating



4 CONDUCTED OUTPUT POWER MEASUREMENT

4.1 Summary

During the process of testing, the EUT was controlled via Agilent Digital Radio Communication tester (E5515C) to ensure the maximum power transmission and proper modulation. This result contains conducted output power for the EUT. In all cases, the measured output power should be greater and within 5% than EMI measurement.

4.2 Conducted Power

CDMA	Conducted Power (dBm)						
BC0	Channel 777(848.31MHz)	Channel 384(836.52MHz)	Channel 1013(824.7MHz)				
ВСО	23.92	23.88	23.99				
CDMA	Conducted Power (dBm)						
CDMA BC1	Channel 1175(1908.75MHz)	Channel 600(1880MHz)	Channel 25(1851.25MHz)				
ВСТ	23.45	23.46	23.47				
CDMA		Conducted Power (dBm)					
BC10	Channel 684(823.1MHz)	Channel 580(820.5MHz)	Channel 476(817.9MHz)				
BCIU	23.90	23.92	23.95				

5. Reference Documents

5.1 Reference Documents for testing

The following document listed in this section is referred for testing.

Reference	Title	Version
ANSI C63.19-2011	American National Standard for Methods of Measurement	2011
	of Compatibility between Wireless Communication Devices	Edition
	and Hearing Aids	
FCC 47 CFR §20.19	Hearing Aid Compatible Mobile Headsets	/
KDB 285076 D01	Equipment Authorization Guidance for Hearing Aid	v04
	Compatibility	



6 OPERATIONAL CONDITIONS DURING TEST

6.1 HAC MEASUREMENT SET-UP

These measurements are performed using the DASY5 NEO automated dosimetric assessment system. It is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland. It consists of high precision robotics system (Stäubli), robot controller, Intel Core2 computer, near-field probe, probe alignment sensor. The robot is a six-axis industrial robot performing precise movements. A cell controller system contains the power supply, robot controller, teach pendant (Joystick), and remote control, is used to drive the robot motors. The PC consists of the HP Intel Core2 1.86 GHz computer with Windows XP system and HAC Measurement Software DASY5 NEO, A/D interface card, monitor, mouse, and keyboard. The Stäubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler (EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.



Fig. 1 HAC Test Measurement Set-up

The DAE4 consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.



6.2 Probe Specification

E-Field Probe Description

Construction One dipole parallel, two dipoles normal to probe axis

Built-in shielding against static charges

PEEK enclosure material

Calibration In air from 100 MHz to 3.0 GHz (absolute accuracy ±6.0%,

k=2)

Frequency 40 MHz to > 6 GHz (can be extended to < 20 MHz)

Linearity: ± 0.2 dB (100 MHz to 3 GHz)

Directivity ± 0.2 dB in air (rotation around probe axis)

± 0.4 dB in air (rotation normal to probe axis)

Dynamic Range 2 V/m to > 1000 V/m; Linearity: ± 0.2 dB

Dimensions Overall length: 330 mm (Tip: 16 mm)

Tip diameter: 8 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 2.5 mm

Application General near-field measurements up to 6 GHz

Field component measurements

Fast automatic scanning in phantoms



[ER3DV6]



6.3 Test Arch Phantom & Phone Positioner

The Test Arch phantom should be positioned horizontally on a stable surface. Reference markings on the Phantom allow the complete setup of all predefined phantom positions and measurement grids by manually teaching three points in the robot. It enables easy and well defined positioning of the phone and validation dipoles as well as simple teaching of the robot (Dimensions: $370 \times 370 \times 370 \text{ mm}$).

The Phone Positioner supports accurate and reliable positioning of any phone with effect on near field $<\pm 0.5$ dB.



Fig. 2 HAC Phantom & Device Holder

6.4 Robotic System Specifications

Specifications

Positioner: Stäubli Unimation Corp. Robot Model: RX160L

Repeatability: ±0.02 mm

No. of Axis: 6

Data Acquisition Electronic (DAE) System

Cell Controller

Processor: Intel Core2 Clock Speed: 1.86 GHz

Operating System: Windows XP

Data Converter

Features: Signal Amplifier, multiplexer, A/D converter, and control logic

Software: DASY5 software

Connecting Lines: Optical downlink for data and status info.

Optical uplink for commands and clock



7 EUT ARRANGEMENT

7.1 WD RF Emission Measurements Reference and Plane

Figure 4 illustrates the references and reference plane that shall be used in the WD emissions measurement.

- The grid is 5 cm by 5 cm area that is divided into 9 evenly sized blocks or sub-grids.
- The grid is centered on the audio frequency output transducer of the WD (speaker or T-coil).
- The grid is located by reference to a reference plane. This reference plane is the planar area that contains the highest point in the area of the WD that normally rests against the user's ear
- The measurement plane is located parallel to the reference plane and 15 mm from it, out from the phone. The grid is located in the measurement plane.

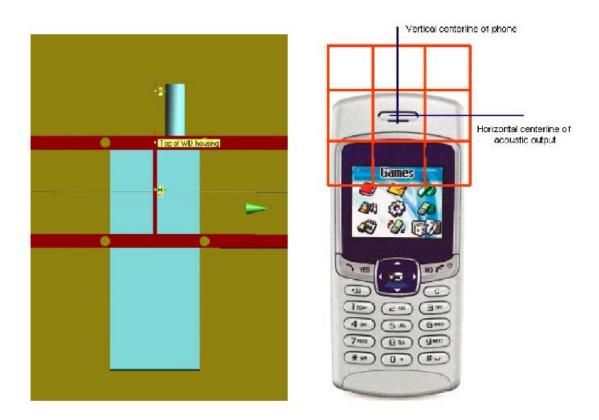


Fig. 3 WD reference and plane for RF emission measurements



8 SYSTEM VALIDATION

8.1 Validation Procedure

Place a dipole antenna meeting the requirements given in ANSI C63.19 in the position normally occupied by the WD. The dipole antenna serves as a known source for an electrical output. Position the E-field probes so that:

- · The probes and their cables are parallel to the coaxial feed of the dipole antenna
- The probe cables and the coaxial feed of the dipole antenna approach the measurement area from opposite directions
- The center point of the probe element(s) are 15 mm from the closest surface of the dipole elements.



Fig. 4 Dipole Validation Setup

8.2 Validation Result

E-Field Scan						
Mode	Frequency	Input Power	Measured ¹	Target ²	Deviation ³	Limit⁴
	(MHz)	(mW)	Value(dBV/m)	Value(dBV/m)	(%)	(%)
CW	835	100	40.51	40.70	-2.16	±25
CW	1880	100	39.25	39.04	2.45	±25

Notes:

- 1. Please refer to the attachment for detailed measurement data and plot.
- 2. Target value is provided by SPEAD in the calibration certificate of specific dipoles.
- 3. Deviation (%) = 100 * (Measured value minus Target value) divided by Target value.
- 4. ANSI C63.19 requires values within \pm 25% are acceptable, of which 12% is deviation and 13% is measurement uncertainty. Values independently validated for the dipole actually used in the measurements should be used, when available.



9 Evaluation of MIF

9.1 Introduction

The MIF (Modulation Interference Factor) is used to classify E-field emission to determine Hearing Aid Compatibility (HAC). It scales the power-averaged signal to the RF audio interference level and is characteristic to a modulation scheme. The HAC standard preferred "indirect" measurement method is based on average field measurement with separate scaling by the MIF. With an Audio Interference Analyzer (AIA) designed by SPEAG specifically for the MIF measurement, these values have been verified by practical measurements on an RF signal modulated with each of the waveforms. The resulting deviations from the simulated values are within the requirements of the HAC standard.

The AIA (Audio Interference Analyzer) is an USB powered electronic sensor to evaluate signals in the frequency range 698 MHz - 6 GHz. It contains RMS detector and audio frequency circuits for sampling of the RF envelope.

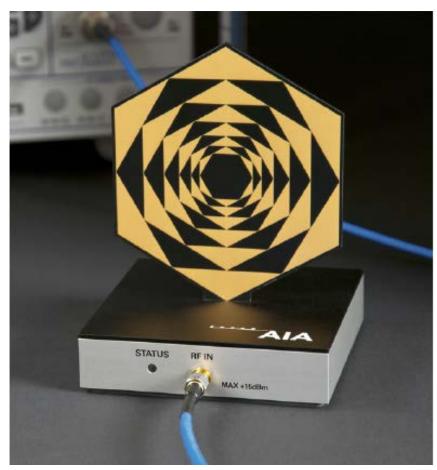


Fig. 5 AIA Front View



9.2 MIF measurement with the AIA

The MIF is measured with the AIA as follows:

- 1. Connect the AIA via USB to the DASY5 PC and verify the configuration settings.
- 2. Couple the RF signal to be evaluated to an AIA via cable or antenna.
- 3. Generate a MIF measurement job for the unknown signal and select the measurement port and timing settings.
- 4. Document the results via the post processor in a report.

9.3 Test equipment for the MIF measurement

No.	Name	Туре	Serial Number	Manufacturer
01	Signal Generator	E4438C	MY49071430	Agilent
02	AIA	SE UMS 170 CB	1029	SPEAG
03	BTS	E5515C	MY50263375	Agilent

9.4 Test signal validation

The signal generator (E4438C) is used to generate a 1GHz signal with different modulation in the below table based on the ANSI C63.19-2011. The measured MIF with AIA are compared with the target values given in ANSI C63.19-2011 table D.3, D.4 and D5.

Pulse modulation	Target MIF	Measured MIF	Deviation
0.5ms pulse, 1000Hz repetition rate	-0.9 dB	-0.9 dB	0 dB
1ms pulse, 100Hz repetition rate	+3.9 dB	+3.7 dB	0.2 dB
0.1ms pulse, 100Hz repetition rate	+10.1 dB	+10.0 dB	0.1 dB
10ms pulse, 10Hz repetition rate	+1.6 dB	+1.7 dB	0.1 dB
Sine-wave modulation	Target MIF	Measured MIF	Deviation
1 kHz, 80% AM	-1.2 dB	-1.3 dB	0.1 dB
1 kHz, 10% AM	-9.1 dB	-9.0 dB	0.1 dB
1 kHz, 1% AM	-19.1 dB	-18.9 dB	0.2 dB
100 Hz, 10% AM	-16.1 dB	-16.0 dB	0.1 dB
10 kHz, 10% AM	-21.5 dB	-21.6 dB	0.1 dB
Transmission protocol	Target MIF	Measured MIF	Deviation
GSM; full-rate version 2; speech codec/handset low	+3.5 dB	+3.47 dB	0.03 dB
WCDMA; speech; speech codec low; AMR 12.2 kb/s	-20.0 dB	-19.8 dB	0.2 dB
CDMA; speech; SO3; RC3; full frame rate; 8kEVRC	-19.0 dB	-19.1 dB	0.1 dB
CDMA; speech; SO3; RC1; 1/8 th frame rate; 8kEVRC	+3.3 dB	+3.44 dB	0.14 dB



9.5 DUT MIF results

Typical MIF levels in ANSI C63.19-2011					
Transmission protocol	Modulation interference factor				
CDMA; speech; SO3; RC1; 1/8 th frame rate; 8kEVRC	+3.3 dB				
CDMA; data; SO55; RC1; full; 8kEVRC	-19.0 dB				

Measured MIF levels					
Band	Channel	Modulation interference factor			
	777	+3.15 dB			
CDMA BC0 (SO3)	384	+3.17 dB			
	1013	+3.17 dB			
	1175	+3.20 dB			
CDMA BC1 (SO3)	600	+3.21 dB			
	25	+3.20 dB			
	684	+3.14 dB			
CDMA BC10 (SO3)	580	+3.15 dB			
	476	+3.17 dB			



10 RF TEST PROCEDUERES

The evaluation was performed with the following procedure:

- 1) Confirm proper operation of the field probe, probe measurement system and other instrumentation and the positioning system.
- 2) Position the WD in its intended test position. The gauge block can simplify this positioning.
- 3) Configure the WD normal operation for maximum rated RF output power, at the desired channel and other operating parameters (e.g., test mode), as intended for the test.
- 4) The center sub-grid shall be centered on the center of the T-Coil mode axial measurement point or the acoustic output, as appropriate. Locate the field probe at the initial test position in the 50 mm by 50 mm grid, which is contained in the measurement plane. If the field alignment method is used, align the probe for maximum field reception.
- 5) Record the reading.
- 6) Scan the entire 50 mm by 50 mm region in equally spaced increments and record the reading at each measurement point. The distance between measurement points shall be sufficient to assure the identification of the maximum reading.
- 7) Identify the five contiguous sub-grids around the center sub-grid whose maximum reading is the lowest of all available choices. This eliminates the three sub-grids with the maximum readings. Thus, the six areas to be used to determine the WD's highest emissions are identified.
- 8) Identify the maximum field reading within the non-excluded sub-grids identified in Step 7)
- 9) Evaluate the MIF and add to the maximum steady-state rms field-strength reading to obtain the RF audio interference level..
- 10) Compare this RF audio interference level with the categories and record the resulting WD category rating.



11 Measurement Results (E-Field)

SO3							
Freq	uency	Measured Value	Power Drift	Category			
MHz	Channel	dB (V/m)	(dB)				
		CDMA B	C0				
848.31	777	27.53	-0.01	M4 (see Fig B.1)			
836.52	384	29.64	0.05	M4 (see Fig B.2)			
824.7	1013	31.24	0.11	M4 (see Fig B.3)			
		CDMA B	C1				
1908.75	1175	19.83	-0.12	M4 (see Fig B.4)			
1880	600	20.68	-0.06	M4 (see Fig B.5)			
1851.25	25	23.37	0.10	M4 (see Fig B.6)			
	CDMA BC10						
823.1	684	31.77	0.11	M4 (see Fig B.7)			
820.5	580	31.63	0.12	M4 (see Fig B.8)			
817.9	476	31.46	-0.12	M4 (see Fig B.9)			

12 ANSI C 63.19-2011 LIMITS

WD RF audio interference level categories in logarithmic units

Emission categories	< 960 MHz					
	E-field emissions					
Category M1	50 to 55	dB (V/m)				
Category M2	45 to 50	dB (V/m)				
Category M3	40 to 45	dB (V/m)				
Category M4	< 40	dB (V/m)				
Emission categories	> 960	0 MHz				
	E-field e	emissions				
Category M1	40 to 45	dB (V/m)				
Category M2	35 to 40	dB (V/m)				
Category M3	30 to 35	dB (V/m)				
Category M4	< 30	dB (V/m)				

13 MEASUREMENT UNCERTAINTY

No.	Error source	Туре	Uncertainty Value (%)	Prob. Dist.	k	C _i	Standard Uncertainty (%) $u_i^{'}$ (%) E	Degree of freedom V _{eff} or v _i
Meas	urement System							
1	Probe Calibration	В	5.	N	1	1	5.1	∞
2	Axial Isotropy	В	4.7	R	$\sqrt{3}$	1	2.7	∞



3 Sensor Displacement B 16.5 R √3 1 9.5 ∞ 4 Boundary Effects B 2.4 R √3 1 1.4 ∞ 5 Linearity B 4.7 R √3 1 2.7 ∞ 6 Scaling to Peak Envelope Power B 2.0 R √3 1 1.2 ∞ 7 System Detection Limit B 1.0 R √3 1 0.6 ∞ 8 Readout Electronics B 0.3 N 1 1 0.3 ∞ 9 Response Time B 0.8 R √3 1 0.5 ∞ 10 Integration Time B 0.8 R √3 1 1.5 ∞ 11 RF Ambient Conditions B 3.0 R √3 1 1.7 ∞ 12 R Reflections B 12.0 R √3 1 0.7 ∞ 13 Probe Positioning A 4.7									
5 Linearity B 4.7 R √3 1 2.7 ∞ 6 Scaling to Peak Envelope Power B 2.0 R √3 1 1.2 ∞ 7 System Detection Limit B 1.0 R √3 1 0.6 ∞ 8 Readout Electronics B 0.3 N 1 1 0.3 ∞ 9 Response Time B 0.8 R √3 1 0.5 ∞ 10 Integration Time B 2.6 R √3 1 1.5 ∞ 11 RF Ambient Conditions B 3.0 R √3 1 1.7 ∞ 12 RF Reflections B 12.0 R √3 1 0.7 ∞ 13 Probe Positioner B 1.2 R √3 1 0.7 ∞ 14 Probe Positioning B 1.0 R <	3	Sensor Displacement	В	16.5	R	$\sqrt{3}$	1	9.5	8
Scaling to Peak Envelope Power	4	Boundary Effects	В	2.4	R	$\sqrt{3}$	1	1.4	8
6 Power	5	Linearity	В	4.7	R	$\sqrt{3}$	1	2.7	∞
8 Readout Electronics B 0.3 N 1 1 0.3 ∞ 9 Response Time B 0.8 R √3 1 0.5 ∞ 10 Integration Time B 2.6 R √3 1 1.5 ∞ 11 RF Ambient Conditions B 3.0 R √3 1 1.7 ∞ 12 RF Reflections B 12.0 R √3 1 0.7 ∞ 13 Probe Positioning A 4.7 R √3 1 0.7 ∞ 14 Probe Positioning A 4.7 R √3 1 0.6 ∞ 15 Extra. And Interpolation B 1.0 R √3 1 0.6 ∞ Text Sample Related 16 Device Positioning Vertical B 4.7 R √3 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R √3 1 0.6 ∞ <	6		В	2.0	R	$\sqrt{3}$	1	1.2	∞
9 Response Time B 0.8 R $\sqrt{3}$ 1 0.5 ∞ 10 Integration Time B 2.6 R $\sqrt{3}$ 1 1.5 ∞ 11 RF Ambient Conditions B 3.0 R $\sqrt{3}$ 1 1.7 ∞ 12 RF Reflections B 12.0 R $\sqrt{3}$ 1 6.9 ∞ 13 Probe Positioner B 1.2 R $\sqrt{3}$ 1 0.7 ∞ 14 Probe Positioning A 4.7 R $\sqrt{3}$ 1 0.7 ∞ 15 Extra. And Interpolation B 1.0 R $\sqrt{3}$ 1 0.6 ∞ Text Sample Related 16 Device Positioning Vertical B 4.7 R $\sqrt{3}$ 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 1.4 ∞	7	System Detection Limit	В	1.0	R	$\sqrt{3}$	1	0.6	8
10 Integration Time	8	Readout Electronics	В	0.3	N	1	1	0.3	∞
11 RF Ambient Conditions B 3.0 R √3 1 1.7 ∞ 12 RF Reflections B 12.0 R √3 1 6.9 ∞ 13 Probe Positioner B 1.2 R √3 1 0.7 ∞ 14 Probe Positioning A 4.7 R √3 1 2.7 ∞ 15 Extra. And Interpolation B 1.0 R √3 1 0.6 ∞ Test Sample Related 16 Device Positioning Vertical B 4.7 R √3 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R √3 1 0.6 ∞ 18 Device Holder and B 2.4 R √3 1 1.4 ∞ 19 Power Drift B 5.0 R √3 1 2.9 ∞ 20 AIA measurement B 12 R √3 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R √3 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty 10 R √3 1 1.4 ∞ 11 RF Ambient Conditions	9	Response Time	В	0.8	R	$\sqrt{3}$	1	0.5	8
12 RF Reflections B 12.0 R $\sqrt{3}$ 1 6.9 ∞ 13 Probe Positioner B 1.2 R $\sqrt{3}$ 1 0.7 ∞ 14 Probe Positioning A 4.7 R $\sqrt{3}$ 1 2.7 ∞ 15 Extra. And Interpolation B 1.0 R $\sqrt{3}$ 1 0.6 ∞ Test Sample Related 16 Device Positioning Vertical B 4.7 R $\sqrt{3}$ 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 0.6 ∞ 18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty $u = 2u$ N $k \in \mathbb{Z}$	10	Integration Time	В	2.6	R	$\sqrt{3}$	1	1.5	∞
13 Probe Positioner B 1.2 R $\sqrt{3}$ 1 0.7 ∞ 14 Probe Positioning A 4.7 R $\sqrt{3}$ 1 2.7 ∞ 15 Extra. And Interpolation B 1.0 R $\sqrt{3}$ 1 0.6 ∞ Test Sample Related 16 Device Positioning Vertical B 4.7 R $\sqrt{3}$ 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 0.6 ∞ 18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 1 2.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty $\omega = 2u$ N $\omega = 2u$	11	RF Ambient Conditions	В	3.0	R	$\sqrt{3}$	1	1.7	8
14 Probe Positioning A 4.7 R $\sqrt{3}$ 1 2.7 ∞ 15 Extra. And Interpolation B 1.0 R $\sqrt{3}$ 1 0.6 ∞ Test Sample Related 16 Device Positioning Vertical B 4.7 R $\sqrt{3}$ 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 0.6 ∞ 18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty $\omega = 2\mu$ N $\omega = 2$	12	RF Reflections	В	12.0	R	$\sqrt{3}$	1	6.9	8
15 Extra. And Interpolation B 1.0 R $\sqrt{3}$ 1 0.6 ∞ Test Sample Related 16 Device Positioning Vertical B 4.7 R $\sqrt{3}$ 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 0.6 ∞ 18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty N $k=2$ 32.4	13	Probe Positioner	В	1.2	R	$\sqrt{3}$	1	0.7	∞
Test Sample Related 16 Device Positioning Vertical B 4.7 R $\sqrt{3}$ 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 0.6 ∞ 18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty	14	Probe Positioning	Α	4.7	R	$\sqrt{3}$	1	2.7	8
16 Device Positioning Vertical B 4.7 R $\sqrt{3}$ 1 2.7 ∞ 17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 0.6 ∞ 18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty $\omega = 2u$ N $\omega = 2u$	15	Extra. And Interpolation	В	1.0	R	$\sqrt{3}$	1	0.6	8
17 Device Positioning Lateral B 1.0 R $\sqrt{3}$ 1 0.6 ∞ 18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty $u = 2u$ N $k=2$ 32.4	Test	Sample Related							
18 Device Holder and Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty	16	Device Positioning Vertical	В	4.7	R	$\sqrt{3}$	1	2.7	∞
18 Phantom B 2.4 R $\sqrt{3}$ 1 1.4 ∞ 19 Power Drift B 5.0 R $\sqrt{3}$ 1 2.9 ∞ 20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty	17	Device Positioning Lateral	В	1.0	R	$\sqrt{3}$	1	0.6	∞
20 AIA measurement B 12 R $\sqrt{3}$ 1 6.9 ∞ Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty $u = 2u$ N $k=2$ 32.4	18		В	2.4	R	$\sqrt{3}$	1	1.4	∞
Phantom and Setup related 21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty $u = 2u$ N $k=2$ 32.4	19	Power Drift	В	5.0	R	$\sqrt{3}$	1	2.9	∞
21 Phantom Thickness B 2.4 R $\sqrt{3}$ 1 1.4 ∞ Combined standard uncertainty(%) Expanded uncertainty $u = 2u$ N $k=2$ 32.4	20	AIA measurement	В	12	R	$\sqrt{3}$	1	6.9	∞
Combined standard uncertainty(%) Expanded uncertainty $u = 2u$ $v = 2u$	Phantom and Setup related								
Expanded uncertainty $u = 2u$ N $k=2$ 32.4	21	Phantom Thickness	В	2.4	R	$\sqrt{3}$	1	1.4	8
u = 2u N k=2 32.4	Comb	Combined standard uncertainty(%)					16.2		
	-	-	ı	$u_e = 2u_c$	N	k=:	2	32.4	



14 MAIN TEST INSTRUMENTS

Table 1: List of Main Instruments

No.	Name	Туре	Serial Number	Calibration Date	Valid Period
01	Signal Generator	E4438C	MY49071430	February 2, 2015	One Year
02	Power meter	NRVD	102196	March 14, 2015	One year
03	Power sensor	NRV-Z5	100596	March 14, 2015	One year
04	Amplifier	60S1G4	0331848	No Calibration Re	quested
05	E-Field Probe	ER3DV6	2428	January 23, 2015	One year
06	HAC Dipole	CD835V3	1023	September 17, 2014	One year
07	HAC Dipole	CD1880V3	1018	September 17, 2014	One year
80	BTS	E5515C	MY50263375	January 30, 2015	One year
09	DAE	SPEAG DAE4	771	January 27, 2015	One year
10	AIA	SE UMS 170 CB	1029	No Calibration Requested	

15 CONCLUSION

The HAC measurement indicates that the EUT complies with the HAC limits of the ANSI C63.19-2011. The total M-rating is $\bf M4$.

END OF REPORT BODY



ANNEX A TEST LAYOUT



Picture A1: HAC RF System Layout



ANNEX B TEST PLOTS

HAC RF E-Field CDMA 835 High – SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA 835; Frequency: 848.31 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

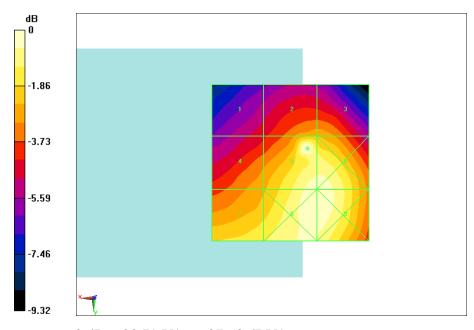
Reference Value = 18.84 V/m; Power Drift = -0.01 dB

Applied MIF = 3.15 dB

RF audio interference level = 27.53 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
23.08 dBV/m	25.11 dBV/m	25.06 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
24.95 dBV/m	27.53 dBV/m	27.25 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
26.22 dBV/m	27.33 dBV/m	27.34 dBV/m



0 dB = 23.79 V/m = 27.53 dBV/m

Fig B.1 HAC RF E-Field CDMA 835 High



HAC RF E-Field CDMA 835 Middle - SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA 835; Frequency: 836.52 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 2/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

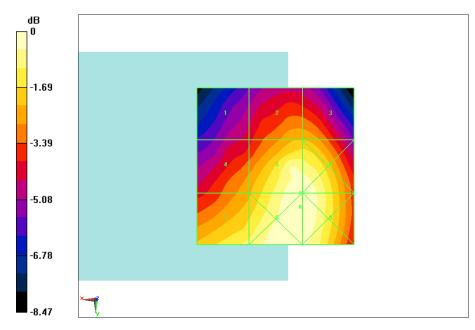
Reference Value = 22.17 V/m; Power Drift = 0.05 dB

Applied MIF = 3.17 dB

RF audio interference level = 29.64 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
25.61 dBV/m	27.52 dBV/m	27.51 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
27.38 dBV/m	29.64 dBV/m	29.63 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
28.82 dBV/m	29.75 dBV/m	29.74 dBV/m



0 dB = 30.71 V/m = 29.75 dBV/m

Fig B.2 HAC RF E-Field CDMA 835 Middle



HAC RF E-Field CDMA 835 Low – SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA 835; Frequency: 824.7 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 3/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

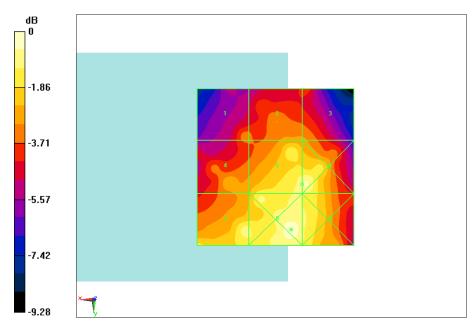
Reference Value = 26.19 V/m; Power Drift = 0.11 dB

Applied MIF = 3.17 dB

RF audio interference level = 31.24 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
28.53 dBV/m	29.11 dBV/m	29.01 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
29.38 dBV/m	31.24 dBV/m	31.36 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
30.92 dBV/m	31.9 dBV/m	30.91 dBV/m



0 dB = 39.35 V/m = 31.90 dBV/m

Fig B.3 HAC RF E-Field CDMA 835 Low



HAC RF E-Field CDMA 1900 High – SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA 1900; Frequency: 1908.75 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

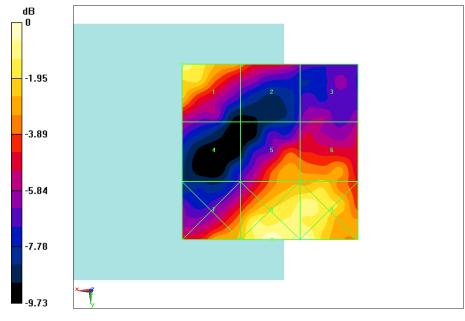
Reference Value = 5.203 V/m; Power Drift = -0.12 dB

Applied MIF = 3.20 dB

RF audio interference level = 19.83 dBV/m

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
19.83 dBV/m	17.66 dBV/m	15.19 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
15.25 dBV/m	18.26 dBV/m	18.43 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
18.49 dBV/m	20.85 dBV/m	20.65 dBV/m



0 dB = 11.03 V/m = 20.85 dBV/m

Fig B.4 HAC RF E-Field CDMA 1900 High



HAC RF E-Field CDMA 1900 Middle - SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA 1900; Frequency: 1880 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 2/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

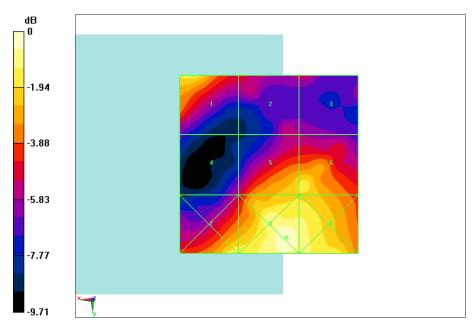
Reference Value = 7.468 V/m; Power Drift = -0.06 dB

Applied MIF = 3.21 dB

RF audio interference level = 20.68 dBV/m

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
20.68 dBV/m	17.31 dBV/m	17.08 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
16.95 dBV/m	20.4 dBV/m	20.58 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
21.07 dBV/m	22.21 dBV/m	21.43 dBV/m



0 dB = 12.90 V/m = 22.21 dBV/m

Fig B.5 HAC RF E-Field CDMA 1900 Middle



HAC RF E-Field CDMA 1900 Low - SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA 1900; Frequency: 1851.25 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 3/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

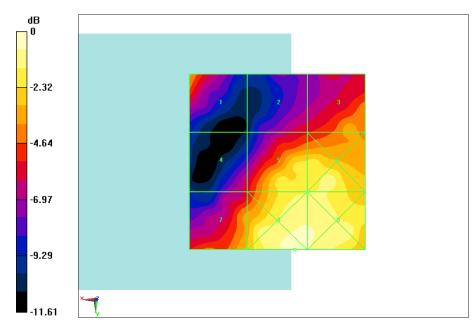
Reference Value = 9.592 V/m; Power Drift = 0.10 dB

Applied MIF = 3.20 dB

RF audio interference level = 23.37 dBV/m

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
21.47 dBV/m	19.45 dBV/m	21.41 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
19.3 dBV/m	23.37 dBV/m	23.87 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
22.06 dBV/m	24.97 dBV/m	24.36 dBV/m



0 dB = 17.72 V/m = 24.97 dBV/m

Fig B.6 HAC RF E-Field CDMA 1900 Low



HAC RF E-Field CDMA BC10 High – SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA BC10; Frequency: 823.1 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

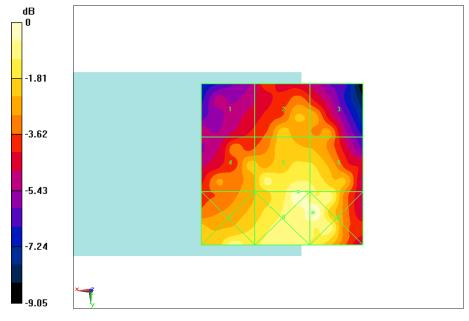
Reference Value = 30.80 V/m; Power Drift = 0.11 dB

Applied MIF = 3.14 dB

RF audio interference level = 31.77 dBV/m

Emission category: M4

Grid 1 M4	Grid 2 M4	Grid 3 M4
28.19 dBV/m	30.12 dBV/m	29.64 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
30.02 dBV/m	31.77 dBV/m	31.17 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
31.43 dBV/m	32.05 dBV/m	32.11 dBV/m



0 dB = 40.34 V/m = 32.11 dBV/m

Fig B.7 HAC RF E-Field CDMA BC10 High



HAC RF E-Field CDMA BC10 Middle - SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA BC10; Frequency: 820.5 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 2/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

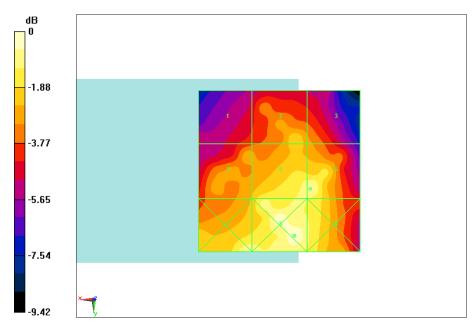
Reference Value = 27.21 V/m; Power Drift = 0.12 dB

Applied MIF = 3.15 dB

RF audio interference level = 31.63 dBV/m

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
28.3 dBV/m	30.23 dBV/m	29.4 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
29.77 dBV/m	31.51 dBV/m	31.63 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
31.72 dBV/m	32.18 dBV/m	31.11 dBV/m



0 dB = 40.63 V/m = 32.18 dBV/m

Fig B.8 HAC RF E-Field CDMA BC10 Middle



HAC RF E-Field CDMA BC10 Low - SO3

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Ambient Temperature:22.7°C

Communication System: CDMA BC10; Frequency: 817.9 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - ER3DV6 - 2011: 15 mm from Probe Center to the Device 3/Hearing Aid

Compatibility Test (101x101x1): Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

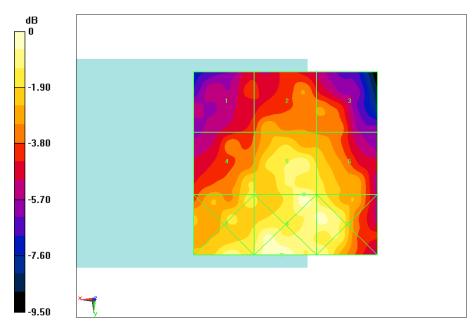
Reference Value = 30.35 V/m; Power Drift = -0.12 dB

Applied MIF = 3.17 dB

RF audio interference level = 31.46 dBV/m

MIF scaled E-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
28.2 dBV/m	29.49 dBV/m	29.04 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
30.29 dBV/m	31.46 dBV/m	30.68 dBV/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
31.45 dBV/m	32.06 dBV/m	31.66 dBV/m



0 dB = 40.09 V/m = 32.06 dBV/m

Fig B.9 HAC RF E-Field CDMA BC10 Low



ANNEX C SYSTEM VALIDATION RESULT

E SCAN of Dipole 835 MHz

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon r = 1$; $\rho = 1000$ kg/m3 Communication System: CW; Frequency: 835 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - measurement distance from the probe sensor center to CD835 Dipole = 15mm/Hearing Aid Compatibility Test (41x361x1): Interpolated grid: dx=0.5000 mm,

dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 117.7 V/m; Power Drift = 0.04 dB

Applied MIF = 0.00 dB

RF audio interference level = 40.51 dBV/m

Emission category: M3

Grid 1 M3	Grid 2 M3	Grid 3 M3
40.32 dBV/m	40.51 dBV/m	40.41 dBV/m
Grid 4 M4	Grid 5 M4	Grid 6 M4
35.52 dBV/m	35.84 dBV/m	35.81 dBV/m
Grid 7 M3	Grid 8 M3	Grid 9 M3
39.97 dBV/m	40.23 dBV/m	40.17 dBV/m



0 dB = 40.51 dBV/m



E SCAN of Dipole 1880 MHz

Date: 2015-5-15

Electronics: DAE4 Sn771

Medium: Air

Medium parameters used: $\sigma = 0$ mho/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Communication System: CW; Frequency: 1880 MHz; Duty Cycle: 1:1

Probe: ER3DV6 - SN2428;ConvF(1, 1, 1)

E Scan - measurement distance from the probe sensor center to CD1880 Dipole = 15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated grid: dx=0.5000 mm,

dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 142.1 V/m; Power Drift = 0.01 dB

Applied MIF = 0.00 dB

RF audio interference level = 39.25 dBV/m

Emission category: M2

Grid 1 M2	Grid 2 M2	Grid 3 M2		
39.02 dBV/m	39.25 dBV/m	39.11 dBV/m		
Grid 4 M2	Grid 5 M2	Grid 6 M2		
36.66 dBV/m	36.86 dBV/m	36.81 dBV/m		
Grid 7 M2	Grid 8 M2	Grid 9 M2		
39.04 dBV/m	39.17 dB V/m	39.08 dBV/m		



0 dB = 39.25 dBV/m



ANNEX D PROBE CALIBRATION CERTIFICATE

E_Probe ER3DV6

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
S Servizio svizzero di taratura
Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Client

CTTL (Auden)

Certificate No: ER3-2428_Jan15

CALIBRATION CERTIFICATE

Object

ER3DV6 - SN:2428

Calibration procedure(s)

QA CAL-02.v8, QA CAL-25.v6

Calibration procedure for E-field probes optimized for close near field

evaluations in air

Calibration date:

January 23, 2015

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).

The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature (22 ± 3)°C and humidity < 70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Cal Date (Certificate No.)	Scheduled Calibration
Power meter E4419B	GB41293874	03-Apr-14 (No. 217-01911)	Apr-15
Power sensor E4412A	MY41498087	03-Apr-14 (No. 217-01911)	Apr-15
Reference 3 dB Attenuator	SN: S5054 (3c)	03-Apr-14 (No. 217-01915)	Apr-15
Reference 20 dB Attenuator	SN: S5277 (20x)	03-Apr-14 (No. 217-01919)	Apr-15
Reference 30 dB Attenuator	SN: S5129 (30b)	03-Apr-14 (No. 217-01920)	Apr-15
Reference Probe ER3DV6	SN: 2328	08-Oct-14 (No. ER3-2328_Oct14)	Oct-15
DAE4	SN: 789	30-Apr-14 (No. DAE4-789_Apr14)	Apr-15
Secondary Standards	ID	Check Date (in house)	Scheduled Check
RF generator HP 8648C	US3642U01700	4-Aug-99 (in house check Apr-13)	In house check: Apr-16
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-14)	In house check: Oct-15

Name Function Signature

Leif Klysner Laboratory Technician

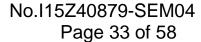
Approved by: Katja Pokovic Technical Manager

Issued: January 26, 2015

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Certificate No: ER3-2428_Jan15

Page 1 of 10





Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary:

NORMx,y,z

sensitivity in free space diode compression point

DCP

crest factor (1/duty_cycle) of the RF signal

A, B, C, D

modulation dependent linearization parameters

Polarization φ

φ rotation around probe axis

Polarization 9

3 rotation around an axis that is in the plane normal to probe axis (at measurement center),

i.e., $\vartheta = 0$ is normal to probe axis

Connector Angle

information used in DASY system to align probe sensor X to the robot coordinate system

Calibration is Performed According to the Following Standards:

- IEEE Std 1309-2005, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", December 2005
- b) CTIA Test Plan for Hearing Aid Compatibility, April 2010.

Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization θ = 0 for XY sensors and θ = 90 for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- NORM(f)x,y,z = NORMx,y,z * frequency_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- Ax,y,z; Bx,y,z; Cx,y,z; Dx,y,z; VRx,y,z: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).



ER3DV6 - SN:2428

January 23, 2015

Probe ER3DV6

SN:2428

Calibrated:

Manufactured: September 11, 2007 January 23, 2015

Calibrated for DASY/EASY Systems (Note: non-compatible with DASY2 system!)

Certificate No: ER3-2428_Jan15

Page 3 of 10



ER3DV6 - SN:2428

January 23, 2015

DASY/EASY - Parameters of Probe: ER3DV6 - SN:2428

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm (µV/(V/m) ²)	1.51	1.58	1.83	± 10.1 %
DCP (mV) ⁸	101.6	99.5	102.3	

Modulation Calibration Parameters

UID	Communication System Name		A dB	B dB√μV	С	D dB	VR mV	Unc ^E (k=2)
0	CW	X	0.0	0.0	1.0	0.00	189.0	±3.8 %
		Y	0.0	0.0	1.0		207.2	
		Z	0.0	0.0	1.0		199.4	
10011- CAB	UMTS-FDD (WCDMA)	X	3.18	66.7	18.9	2.91	112.3	±0.7 %
		Y	3.14	66.0	18.2		123.4	
		Z	3.14	66.4	18.4		116.3	
10021- DAB	GSM-FDD (TDMA, GMSK)	X	16.25	97.6	28.0	9.39	106.6	±1.7 %
		Y	9.84	90.3	25.6		112.7	
		Z	18.91	97.3	27.6		121.7	
10039- CAB	CDMA2000 (1xRTT, RC1)	X	4.67	66.4	19.2	4.57	113.6	±0.9 %
		Y	4.71	66.5	19.1		125.0	
		Z	4.49	66.0	18.8		115.6	
10081- CAB	CDMA2000 (1xRTT, RC3)	X	3.75	65.2	18.3	3.97	110.4	±0.7 %
		Y	3.78	65.2	18.2		122.0	
		Z	3.69	65.3	18.3		113.2	

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: ER3-2428_Jan15

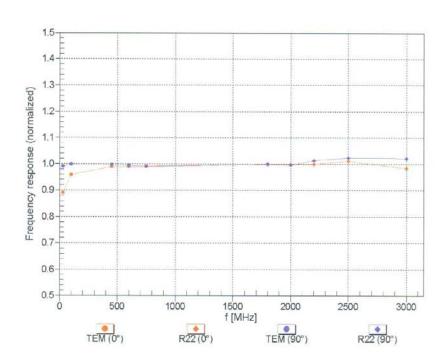
⁸ Numerical linearization parameter: uncertainty not required.

E Uncertainty is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.



ER3DV6 - SN:2428 January 23, 2015

Frequency Response of E-Field (TEM-Cell:ifi110 EXX, Waveguide: R22)



Uncertainty of Frequency Response of E-field: ± 6.3% (k=2)

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Certificate No: ER3-2428_Jan15

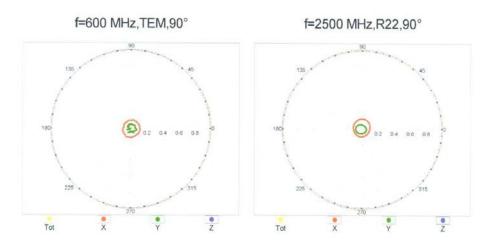


ER3DV6 - SN:2428 January 23, 2015

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$



Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$

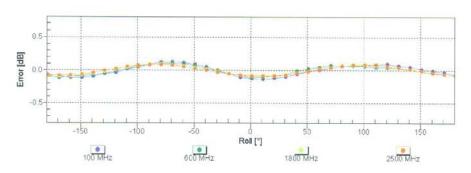


Certificate No: ER3-2428_Jan15 Page 6 of 10



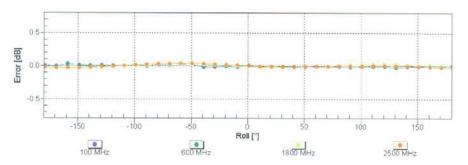
January 23, 2015

Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$

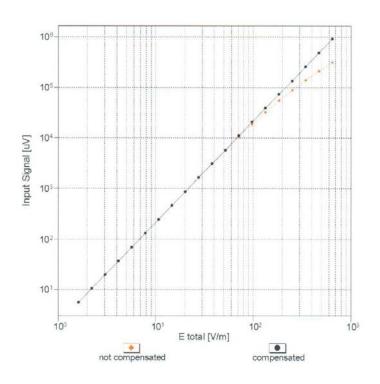


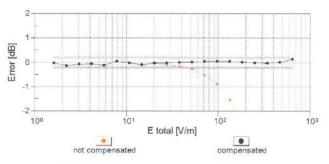
Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)



January 23, 2015

Dynamic Range f(E-field) (TEM cell , f = 900 MHz)





Uncertainty of Linearity Assessment: ± 0.6% (k=2)

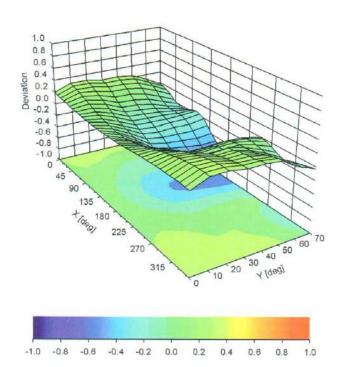
Certificate No: ER3-2428_Jan15

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January 23, 2015

Deviation from Isotropy in Air Error (\phi, \text{ 9), f = 900 MHz}



Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)



January 23, 2015

DASY/EASY - Parameters of Probe: ER3DV6 - SN:2428

Other Probe Parameters

Sensor Arrangement	Rectangular
Connector Angle (°)	-39.1
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	10 mm
Tip Diameter	8 mm
Probe Tip to Sensor X Calibration Point	2.5 mm
Probe Tip to Sensor Y Calibration Point	2.5 mm
Probe Tip to Sensor Z Calibration Point	2.5 mm



ANNEX E DIPOLE CALIBRATION CERTIFICATE

Dipole 835 MHz

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst Service suisse d'étalonnage C Servizio svizzero di taratura **Swiss Calibration Service**

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

CALIBRATION C	CERTIFICATI		
Object	CD835V3 - SN:	1023	
Calibration procedure(s)	QA CAL-20.v6 Calibration proce	edure for dipoles in air	
Calibration date:	September 17, 2	014	
Calibration Equipment used (M&	TE critical for calibration)	ry facility: environment temperature (22 ± 3)°(
Primary Standards	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Power meter EPM-442A Power sensor HP 8481A	GB37480704 US37292783	09-Oct-13 (No. 217-01827)	Oct-14
		09-Oct-13 (No. 217-01827)	Oct-14
ower sensor HP 8481A vpe-N mismatch combination	MY41092317 SN: 5047.2 / 06327	09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921)	Oct-14
Probe ER3DV6	SN: 2336	30-Dec-13 (No. ER3-2336_Dec13)	Apr-15 Dec-14
Probe H3DV6	SN: 6065	30-Dec-13 (No. H3-6065_Dec13)	Dec-14
DAE4	SN: 781	12-Sep-14 (No. DAE4-781_Sep14)	Sep-15
Secondary Standards	ID#	Check Date (in house)	Scheduled Check
Power meter Agilent 4419B	SN: GB40202831	29-Oct-13 (in house check Oct-13)	In house check: Oct-15
Power sensor HP E4412A	SN: MY41498700	11-Oct-13 (in house check Oct-13)	In house check: Oct-15
	SN: MY41502623	11-Oct-13 (in house check Oct-13)	
			In house check: Oct-15
Network Analyzer HP 8753E	US37390585	18-Oct-01 (in house check Oct-13)	In house check: Oct-14
Network Analyzer HP 8753E	US37390585 SN: 832283/011	18-Oct-01 (in house check Oct-13) 27-Aug-12 (in house check Oct-13)	
Network Analyzer HP 8753E			In house check: Oct-14
Power sensor HP E4412A Network Analyzer HP 8753E RF generator R&S SMT-06 Calibrated by:	SN: 832283/011	27-Aug-12 (in house check Oct-13)	In house check: Oct-14 In house check: Oct-16

Certificate No: CD835V3-1023_Sep14

Page 1 of 8

This calibration certificate shall not be reproduced except in full without written approval of the laboratory.

Issued: September 22, 2014



Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





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References

- [1] ANSI-C63.19-2007 American National Standard for Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.
- [2] ANSI-C63.19-2011 American National Standard, Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
 (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
 In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a
 distance of 10 mm (15 mm for [2]) above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
 figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
 is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
 directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1] and [2], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 10 mm (15 mm for [2]) (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.
- H-field distribution: H-field is measured with an isotropic H-field probe with 100mW forward power to the
 antenna feed point, in the x-y-plane. The scan area and sensor distance is equivalent to the E-field scan. The
 maximum of the field is available at the center (subgrid 5) above the feed point. The H-field value stated as
 calibration value represents the maximum of the interpolated H-field, 10mm above the dipole surface at the
 feed point.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Certificate No: CD835V3-1023_Sep14



Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.8.8
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	10 mm	
Scan resolution	dx, dy = 5 mm	
Frequency	835 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 835 MHz

Averaged maximum above arm

H-field 10 mm above dipole surface	condition	interpolated maximum
Maximum measured	100 mW input power	0.459 A/m ± 8.2 % (k=2)
E-field 10 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	170.0 V/m = 44.61 dBV/m
Maximum measured above low end	100 mW input power	158.3 V/m = 43.99 dBV/m
Averaged maximum above arm	100 mW input power	164.2 V/m ± 12.8 % (k=2)
E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	108.3 V/m = 40.69 dBV/m
Maximum measured above low end	100 mW input power	104.9 V/m = 40.41 dBV/m
Averaged maximum above arm	100 mW input power	106.6 V/m ± 12.8 % (k=2)



Appendix (Additional assessments outside the scope of SCS108)

Antenna Parameters

Frequency	Return Loss	Impedance
800 MHz	16.7 dB	48.6 Ω - 14.4 jΩ
835 MHz	24.0 dB	45.5 Ω + 4.0 jΩ
900 MHz	16.5 dB	51.6 Ω + 15.4 jΩ
950 MHz	20.3 dB	51.4 Ω - 9.7 jΩ
960 MHz	16.5 dB	42.9 Ω - 12.1 jΩ

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

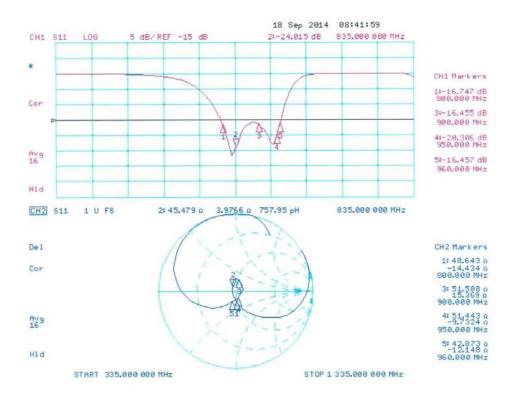
The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.



Impedance Measurement Plot





DASY5 H-field Result

Date: 17.09.2014

Test Laboratory: SPEAG Lab2

DUT: HAC-Dipole 835 MHz; Type: CD835V3; Serial: CD835V3 - SN: 1023

Communication System: UID 0 - CW ; Frequency: 835 MHz Medium parameters used: $\sigma=0$ S/m, $\epsilon_r=1$; $\rho=1$ kg/m³

Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

- Probe: H3DV6 SN6065; ; Calibrated: 30.12.2013
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 12.09.2014
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.8.8(1222); SEMCAD X 14.6.10(7331)

Dipole H-Field measurement @ 835MHz/H-Scan - 835MHz d=10mm/Hearing Aid Compatibility Test (41x361x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

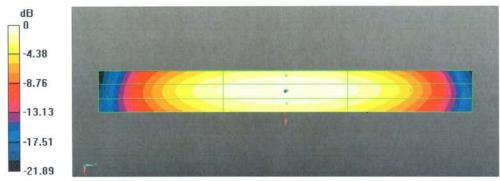
Reference Value = 0.4880 A/m; Power Drift = -0.02 dB

PMR not calibrated. PMF = 1.000 is applied.

H-field emissions = 0.4587 A/m Near-field category: M4 (AWF 0 dB)

PMF scaled H-field

Grid 1 M4	Grid 2 M4	Grid 3 M4
0.378 A/m	0.400 A/m	0.383 A/m
	Grid 5 M4	
0.427 A/m	0.459 A/m	0.441 A/m
Grid 7 M4	Grid 8 M4	Grid 9 M4
0.379 A/m	0.410 A/m	0.394 A/m



0 dB = 0.4587 A/m = -6.77 dBA/m



DASY5 E-field Result

Date: 17.09.2014

Test Laboratory: SPEAG Lab2

DUT: HAC-Dipole 835 MHz; Type: CD835V3; Serial: CD835V3 - SN: 1023

Communication System: UID 0 - CW ; Frequency: 835 MHz Medium parameters used: $\sigma = 0$ S/m, $\epsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

Probe: ER3DV6 - SN2336; ConvF(1, 1, 1); Calibrated: 30.12.2013;

• Sensor-Surface: (Fix Surface)

• Electronics: DAE4 Sn781; Calibrated: 12.09.2014

Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070

DASY52 52.8.8(1222); SEMCAD X 14.6.10(7331)

Dipole E-Field measurement @ 835MHz/E-Scan - 835MHz d=10mm/Hearing Aid Compatibility Test (41x361x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 121.3 V/m; Power Drift = -0.02 dB

Applied MIF = 0.00 dB

RF audio interference level = 44.61 dBV/m

Emission category: M3

MIF scaled E-field

Grid 2 M3 44.61 dBV/m	Grid 3 M3 44.37 dBV/m
Grid 5 M4 38.91 dBV/m	Grid 6 M4 38.82 dBV/m
Grid 8 M3 43.99 dBV/m	Grid 9 M3 43.89 dBV/m



Dipole E-Field measurement @ 835MHz/E-Scan - 835MHz d=15mm/Hearing Aid Compatibility Test (41x361x1): Interpolated

grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm

Reference Value = 120.8 V/m; Power Drift = 0.00 dB

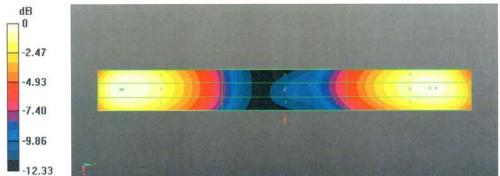
Applied MIF = 0.00 dB

RF audio interference level = 40.70 dBV/m

Emission category: M3

MIF scaled E-field

	Grid 2 M3 40.69 dBV/m	Grid 3 M3 40.6 dBV/m
Grid 4 M4		Grid 6 M4
Grid 7 M3		Grid 9 M3



0 dB = 170.0 V/m = 44.61 dBV/m



Dipole 1880 MHz

Calibration Laboratory of Schmid & Partner Engineering AG

Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





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Servizio svizzero di taratura
Swiss Calibration Service

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Client

CTTL (Auden)

Certificate No: CD1880V3-1018 Sep14

Accreditation No.: SCS 108

Object	CD1880V3 - SN:	1018	
Calibration procedure(s)	QA CAL-20.v6 Calibration proce	dure for dipoles in air	
Calibration date:	September 17, 20	014	
The measurements and the unce	rtainties with confidence pr	onal standards, which realize the physical units robability are given on the following pages and a y facility: environment temperature $(22 \pm 3)^{\circ}$ C a	are part of the certificate.
Calibration Equipment used (M&T	FE critical for calibration)		
free material free free			
	ID#	Cal Date (Certificate No.)	Scheduled Calibration
Primary Standards	ID # GB37480704	Cal Date (Certificate No.) 09-Oct-13 (No. 217-01827)	Scheduled Calibration Oct-14
Primary Standards Power meter EPM-442A			
Primary Standards Power meter EPM-442A Power sensor HP 8481A	GB37480704	09-Oct-13 (No. 217-01827)	Oct-14
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A	GB37480704 US37292783	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827)	Oct-14 Oct-14
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination	GB37480704 US37292783 MY41092317	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828)	Oct-14 Oct-14 Oct-14
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921)	Oct-14 Oct-14 Oct-14 Apr-15
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Fype-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065 SN: 781	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13) 12-Sep-14 (No. DAE4-781_Sep14)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14 Sep-15
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065 SN: 781	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14 Sep-15 Scheduled Check
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065 SN: 781 ID #	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 29-Oct-13 (in house check Oct-13)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14 Sep-15 Scheduled Check In house check: Oct-15
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP E4412A	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065 SN: 781 ID # SN: GB40202831 SN: MY41498700	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 29-Oct-13 (in house check Oct-13) 11-Oct-13 (in house check Oct-13)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14 Sep-15 Scheduled Check In house check: Oct-15 In house check: Oct-15
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP E4412A Network Analyzer HP 8753E	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065 SN: 781 ID # SN: GB40202831 SN: MY41498700 SN: MY41502623	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 29-Oct-13 (in house check Oct-13) 11-Oct-13 (in house check Oct-13)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14 Sep-15 Scheduled Check In house check: Oct-15 In house check: Oct-15 In house check: Oct-15
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP E4412A Network Analyzer HP 8753E	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065 SN: 781 ID # SN: GB40202831 SN: MY41498700 SN: MY41502623 US37390585	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 29-Oct-13 (in house check Oct-13) 11-Oct-13 (in house check Oct-13) 11-Oct-13 (in house check Oct-13) 18-Oct-01 (in house check Oct-13)	Oct-14 Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14 Sep-15 Scheduled Check In house check: Oct-15 In house check: Oct-15 In house check: Oct-15 In house check: Oct-15
Primary Standards Power meter EPM-442A Power sensor HP 8481A Power sensor HP 8481A Type-N mismatch combination Probe ER3DV6 Probe H3DV6 DAE4 Secondary Standards Power meter Agilent 4419B Power sensor HP E4412A Power sensor HP E4412A Network Analyzer HP 8753E RF generator R&S SMT-06 Calibrated by:	GB37480704 US37292783 MY41092317 SN: 5047.2 / 06327 SN: 2336 SN: 6065 SN: 781 ID # SN: GB40202831 SN: MY41498700 SN: MY41502623 US37390585 SN: 832283/011	09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01827) 09-Oct-13 (No. 217-01828) 03-Apr-14 (No. 217-01921) 30-Dec-13 (No. ER3-2336_Dec13) 30-Dec-13 (No. H3-6065_Dec13) 12-Sep-14 (No. DAE4-781_Sep14) Check Date (in house) 29-Oct-13 (in house check Oct-13) 11-Oct-13 (in house check Oct-13) 11-Oct-13 (in house check Oct-13) 18-Oct-01 (in house check Oct-13) 27-Aug-12 (in house check Oct-13)	Oct-14 Oct-14 Oct-14 Apr-15 Dec-14 Dec-14 Sep-15 Scheduled Check In house check: Oct-15 In house check: Oct-15 In house check: Oct-15 In house check: Oct-14 In house check: Oct-16

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Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst
C Service suisse d'étalonnage
Servizio svizzero di taratura
Swiss Calibration Service

Accreditation No.: SCS 108

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

References

- [1] ANSI-C63.19-2007 American National Standard for Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.
- ANSI-C63.19-2011
 American National Standard, Methods of Measurement of Compatibility between Wireless Communications
 Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
 (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
 In coincidence with the standards [1], the measurement planes (probe sensor center) are selected to be at a
 distance of 10 mm (15 mm for [2]) above the top metal edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
 figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
 is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
 directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY5 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1] and [2], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 10 mm (15 mm for [2]) (in z) above the metal top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, in the plane above the dipole surface.
- H-field distribution: H-field is measured with an isotropic H-field probe with 100mW forward power to the
 antenna feed point, in the x-y-plane. The scan area and sensor distance is equivalent to the E-field scan. The
 maximum of the field is available at the center (subgrid 5) above the feed point. The H-field value stated as
 calibration value represents the maximum of the interpolated H-field, 10mm above the dipole surface at the
 feed point.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY5	V52.8.8
Phantom	HAC Test Arch	
Distance Dipole Top - Probe Center	10 mm	
Scan resolution	dx, $dy = 5 mm$	
Frequency	1880 MHz ± 1 MHz	
Input power drift	< 0.05 dB	

Maximum Field values at 1880 MHz

H-field 10 mm above dipole surface	condition	interpolated maximum
Maximum measured	100 mW input power	0.456 A/m ± 8.2 % (k=2)

E-field 10 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	143.0 V/m = 43.11 dBV/m
Maximum measured above low end	100 mW input power	134.6 V/m = 42.58 dBV/m
Averaged maximum above arm	100 mW input power	138.8 V/m ± 12.8 % (k=2)

E-field 15 mm above dipole surface	condition	Interpolated maximum
Maximum measured above high end	100 mW input power	89.5 V/m = 39.04 dBV/m
Maximum measured above low end	100 mW input power	88.9 V/m = 38.97 dBV/m
Averaged maximum above arm	100 mW input power	89.2 V/m ± 12.8 % (k=2)

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Appendix (Additional assessments outside the scope of SCS108)

Antenna Parameters

Frequency	Return Loss	Impedance
1730 MHz	27.1 dB	53.3 Ω + 3.2 jΩ
1880 MHz	21.6 dB	49.2 Ω + 8.3 jΩ
1900 MHz	22.9 dB	51.6 Ω + 7.1 jΩ
1950 MHz	32.8 dB	51.4 Ω + 1.9 jΩ
2000 MHz	19.2 dB	41.4 Ω + 5.3 jΩ

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

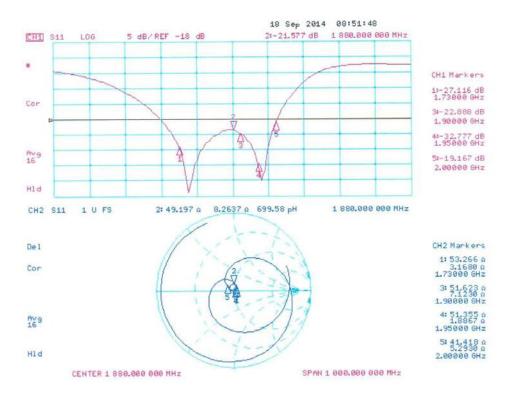
The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.



Impedance Measurement Plot





DASY5 H-field Result

Date: 17.09.2014

Test Laboratory: SPEAG Lab2

DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: CD1880V3 - SN: 1018

Communication System: UID 0 - CW ; Frequency: 1880 MHz Medium parameters used: $\sigma=0$ S/m, $\epsilon_r=1$; $\rho=1$ kg/m 3

Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

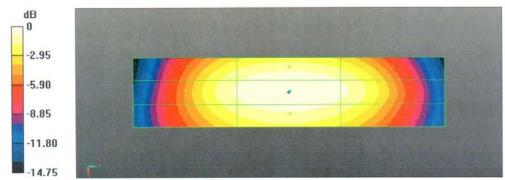
- Probe: H3DV6 SN6065; ; Calibrated: 30.12.2013
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn781; Calibrated: 12.09.2014
- Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070
- DASY52 52.8.8(1222); SEMCAD X 14.6.10(7331)

Dipole H-Field measurement @ 1880MHz/H-Scan - 1880MHz d=10mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm
Device Reference Point: 0, 0, -6.3 mm
Reference Value = 0.4820 A/m; Power Drift = 0.02 dB
PMR not calibrated. PMF = 1.000 is applied.
H-field emissions = 0.4565 A/m
Near-field category: M2 (AWF 0 dB)

PMF scaled H-field

Grid 1 M2	Grid 2 M2	Grid 3 M2
0.394 A/m	0.416 A/m	0.400 A/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
0.431 A/m	0.456 A/m	0.439 A/m
Grid 7 M2	Grid 8 M2	Grid 9 M2
0.394 A/m	0.422 A/m	0.405 A/m



0 dB = 0.4565 A/m = -6.81 dBA/m

Certificate No: CD1880V3-1018_Sep14



DASY5 E-field Result

Date: 17.09.2014

Test Laboratory: SPEAG Lab2

DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: CD1880V3 - SN: 1018

Communication System: UID 0 - CW; Frequency: 1880 MHz Medium parameters used: $\sigma = 0$ S/m, $\varepsilon_r = 1$; $\rho = 1000$ kg/m³

Phantom section: RF Section

Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2011)

DASY52 Configuration:

Probe: ER3DV6 - SN2336; ConvF(1, 1, 1); Calibrated: 30.12.2013;

• Sensor-Surface: (Fix Surface)

Electronics: DAE4 Sn781; Calibrated: 12.09.2014

· Phantom: HAC Test Arch with AMCC; Type: SD HAC P01 BA; Serial: 1070

DASY52 52.8.8(1222); SEMCAD X 14.6.10(7331)

Dipole E-Field measurement @ 1880MHz/E-Scan - 1880MHz d=10mm/Hearing Aid Compatibility Test (41x181x1):

Interpolated grid: dx=0.5000 mm, dy=0.5000 mm

Device Reference Point: 0, 0, -6.3 mm

Reference Value = 141.0 V/m; Power Drift = -0.01 dB Applied MIF = 0.00 dB

RF audio interference level = 43.11 dBV/m

Emission category: M1

MIF scaled E-field

Grid 1 M1	Grid 2 M1	Grid 3 M1
42.58 dBV/m	43.11 dBV/m	42.82 dBV/m
Grid 4 M2	Grid 5 M2	Grid 6 M2
38.25 dBV/m	38.77 dBV/m	38.69 dBV/m
Grid 7 M1	Grid 8 M1	Grid 9 M1
42.18 dBV/m	42.58 dBV/m	42.44 dBV/m



Dipole E-Field measurement @ 1880MHz/E-Scan - 1880MHz d=15mm/Hearing Aid Compatibility Test (41x181x1): Interpolated

grid: dx=0.5000 mm, dy=0.5000 mm Device Reference Point: 0, 0, -6.3 mm

Reference Value = 140.9 V/m; Power Drift = -0.02 dB

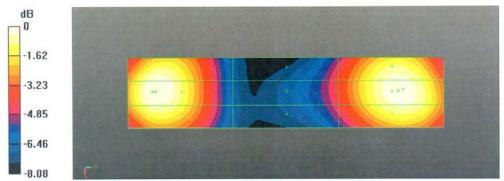
Applied MIF = 0.00 dB

RF audio interference level = 39.04 dBV/m

Emission category: M2

MIF scaled E-field

	Grid 2 M2 39.04 dBV/m	
No. of Contract Contr	Grid 5 M2 36.65 dBV/m	Grid 6 M2 36.61 dBV/m
PERMIT TARRET	Grid 8 M2 38.97 dBV/m	Grid 9 M2 38.87 dBV/m



0 dB = 143.0 V/m = 43.11 dBV/m



The photos of HAC test are presented in the additional document:

Appendix to test report no. I15Z40879-SEM04/05

The photos of HAC test